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18-Bit, Single-Channel, Low-Noise, Voltage-Output DIGITAL-TO-ANALOG CONVERTER

FEATURES

- Relative Accuracy: ±2 LSB
- 18-Bit Monotonic Over Temperature Range
- Low-Noise: 24nV/√Hz
- Fast Settling: 5μs
- On-Chip Output Buffer Amplifier with Rail-to-Rail Operation
- Single Power Supply: +4.75V to +5.5V
- DAC Loading Control
- Selectable Power-On Reset to Zero-Scale or Midscale
- Power-Down Mode
- Unipolar Straight Binary or 2s Complement Input Mode
- Fast SPI™ Interface with Schmitt-Triggered Inputs:
 - Up To 50MHz, 1.8V/3V/5V Logic
- Small Package: QFN-24, 4mm × 4mm

APPLICATIONS

- Industrial Process Control
- Data Acquisition Systems
- Automatic Test Equipment
- Communications
- Optical Networking

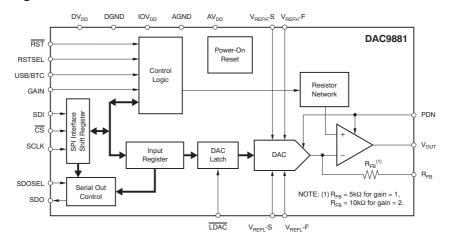
DESCRIPTION

The DAC9881 is an 18-bit, single-channel, voltage-output digital-to-analog converter (DAC) that offers low-power operation and a flexible SPI serial interface. It also features 18-bit monotonicity, excellent linearity, and fast settling time. The on-chip precision output amplifier allows rail-to-rail output swing to be achieved over the full supply range of 4.75V to 5.5V.

The device supports a standard SPI serial interface capable of operating with input data clock frequencies up to 50MHz. The DAC9881 requires an external reference voltage to set the output range of the DAC channel. A programmable power-on reset circuit is also incorporated into the device to ensure that the DAC output powers up at zero-scale or midscale, and remains there until a valid write command.

Additionally, the device has the capability to function in either unipolar straight binary or 2s complement mode. The DAC9881 provides a power-down feature, accessed over the PDN pin, that reduces the current consumption to 25µA at 5V. Power consumption is 6mW at 5V, reducing to 125µW in power-down mode.

The DAC9881 is available in a 4mm \times 4mm QFN-24 package with a specified operating temperature range of -40°C to +85°C.



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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

ORDERING INFORMATION(1)

PRODUCT	PACKAGE- LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	PACKAGE MARKING
DAC9881	QFN-24	RGE	-40°C to +85°C	DAC9881

⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum at the end of this data sheet, or see the TI website at www.ti.com.

ABSOLUTE MAXIMUM RATINGS(1)

Over operating free-air temperature range (unless otherwise noted).

			DAC9881	UNIT
AV _{DD} to AGND			-0.3 to 6	V
DV _{DD} to DGND			-0.3 to 6	V
IOV _{DD} to DGND		-	-0.3 to 6	V
Digital input voltage to DGND		12.3	-0.3 to IOV _{DD} + 0.3	V
V _{OUT} to AGND		26 75	-0.3 to AV _{DD} + 0.3	V
Operating temperature range		132	-40 to +85	°C
Storage temperature range			-65 to +150	°C
Maximum junction temperature (T	J max)		+150	°C
ESD ratings	Human body model (HBM)		3000	V
ESD ratings	Charged device model (CDM)		1000	V

⁽¹⁾ Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. Exposure to absolute maximum conditions for extended periods may affect device reliability.

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ELECTRICAL CHARACTERISTICS

All specifications at $T_A = T_{MIN}$ to T_{MAX} , $AV_{DD} = DV_{DD} = +4.75V$ to +5.5V, $IOV_{DD} = +1.8V$ to +5.5V, and gain = 1X mode, unless otherwise noted.

			D/	AC9881		
PARAMETER		CONDITIONS	MIN	TYP	MAX	UNIT
ACCURACY			I.			
Linearity error	Measured by line pass	sing through codes 2048 and 260096		±1	±2	LSB
Differential linearity error	Measured by line pass	sing through codes 2048 and 260096		±0.5	±1	LSB
Monotonicity			18			Bits
	$T_A = +25^{\circ}C$, code = 20	048			±16	LSB
Zero-scale error	T_{MIN} to T_{MAX} , code = 2	2048			±32	LSB
Zero-scale drift	Code = 2048			±0.5	±1	ppm/°C of FSR
Gain error	T _A = +25°C, measured and 260096	d by line passing through codes 2048		±16	±32	LSB
Gain temperature drift	Measured by line pass	sing through codes 2048 and 260096		±0.5	±1	ppm/°C
PSRR	V _{OUT} = full-scale, AV _D	_D = +5V ±10%			32	LSB/V
ANALOG OUTPUT(1)						
Voltage output ⁽²⁾			0		AV_{DD}	V
	Device operating for 500 hours 5					ppm of FSR
Output voltage drift vs time	Device operating for 1	000 hours	44	8		ppm of FSR
Output current		2	The same	2.5		mA
Maximum load capacitance		20 13	-0.	200		pF
Short-circuit current		132		+31, –50		mA
REFERENCE INPUT ⁽¹⁾						
V _{REFH} input voltage range	$AV_{DD} = +5.5V$		1.25	5.0	AV_{DD}	V
V _{REFH} input capacitance				5		pF
V _{REFH} input impedance				4.5		kΩ
V _{REFL} input voltage range			-0.2	0	+0.2	V
V _{REFL} input capacitance				4.5		pF
V _{REFL} input impedance				5		kΩ
DYNAMIC PERFORMANCE(1)			1			
Settling time	To ±0.003% FS, R _L = 3C000h	$10k\Omega$, $C_L = 50pF$, code 04000h to		5		μs
Slew rate	From 10% to 90% of 0)V to +5V		2.5		V/µs
		V _{REFH} = 5V, gain = 1X mode		37		nV-s
		V _{REFH} = 2.5V, gain = 1X mode		18		nV-s
Code change glitch	Code = 1FFFFh to 20000h to 1FFFFh	V _{REFH} = 1.25V, gain = 1X mode		9		nV-s
		V _{REFH} = 2.5V, gain = 2X mode		21		nV-s
		V _{REFH} = 1.25V, gain = 2X mode		10		nV-s
Digital feedthrough				1		nV-s
Output poins welters deser	f = 1kHz to 100kHz,	Gain = 1		24	30	nV/√ Hz
Output noise voltage density	full-scale output	Gain = 2		40	48	nV/√ Hz
Output noise voltage	f = 0.1Hz to 10Hz, full-	-scale output		2		μV_{PP}

 ⁽¹⁾ Ensured by design. Not production tested.
(2) The output from the V_{OUT} pin = [(V_{REFH} - V_{REFL})/262144] × CODE × Buffer GAIN + V_{REFL}. The maximum range of V_{OUT} is 0V to AV_{DD}. The full-scale of the output must be less than AV_{DD}; otherwise, output saturation occurs.



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ELECTRICAL CHARACTERISTICS (continued)

All specifications at $T_A = T_{MIN}$ to T_{MAX} , $AV_{DD} = DV_{DD} = +4.75V$ to +5.5V, $IOV_{DD} = +1.8V$ to +5.5V, and gain = 1X mode, unless otherwise noted.

		DA			
PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
DIGITAL INPUTS(3)				•	
	IOV _{DD} = 4.5V to 5.5V	3.8		$IOV_{DD} + 0.3$	V
High-level input voltage, $V_{\rm IH}$	IOV _{DD} = 2.7V to 3.3V	2.1		$IOV_{DD} + 0.3$	V
	IOV _{DD} = 1.7V to 2.0V	1.5		IOV _{DD} + 0.3	V
	IOV _{DD} = 4.5V to 5.5V	-0.3		0.8	V
Low-level input voltage, V _{IL}	IOV _{DD} = 2.7V to 3.3V	-0.3		0.6	V
	IOV _{DD} = 1.7V to 2.0V	-0.3		0.3	V
Digital input current (I _{IN})			±1	±10	μΑ
Digital input capacitance			5		pF
DIGITAL OUTPUT ⁽³⁾					
I link lavel and only only and M	$IOV_{DD} = 2.7V \text{ to } 5.5V, I_{OH} = -1\text{mA}$	IOV _{DD} - 0.2			V
High-level output voltage, V _{OH}	$IOV_{DD} = 1.7V$ to 2.0V, $I_{OH} = -500\mu A$	IOV _{DD} - 0.2			V
1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	IOV _{DD} = 2.7V to 5.5V, I _{OL} = 1mA	.a		0.2	V
Low-level output voltage, V _{OL}	$IOV_{DD} = 1.7 \text{ to } 2.0V, I_{OL} = 500\mu\text{A}$	1 1		0.2	V
POWER SUPPLY		7. 33 4			
AV _{DD}	B	+4.75		+5.5	V
DV _{DD}	26.73	+4.75	-	+5.5	V
IOV _{DD}	130	+1.7		DV_DD	V
Al _{DD}	$V_{IH} = IOV_{DD}, V_{IL} = DGND$			1.5	mA
DI _{DD}	$V_{IH} = IOV_{DD}, V_{IL} = DGND$		1	10	μΑ
IOI _{DD}	$V_{IH} = IOV_{DD}, V_{IL} = DGND$		1	10	μΑ
Al _{DD} power-down	PDN = IOV _{DD}		25	50	μΑ
Power dissipation	$AV_{DD} = DV_{DD} = 5.0V$		6	7.5	mW
TEMPERATURE RANGE					
Specified performance		-40		+85	°C

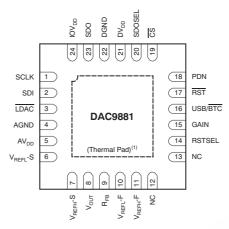
⁽³⁾ Ensured by design. Not production tested.



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PIN CONFIGURATION

RGE PACKAGE⁽¹⁾ QFN-24 (TOP VIEW)



(1) The thermal pad is internally connected to the substrate. This pad can be connected to the analog ground or left floating. Keep the thermal pad separate from the digital ground, if possible.

TERMINAL FUNCTIONS

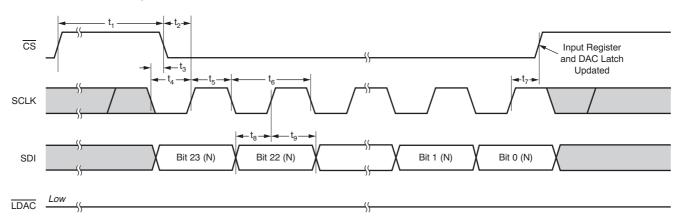
TERMINAL								
NO.	NAME	I/O	DESCRIPTION					
1	SCLK	ı	SPI bus serial clock input					
2	SDI	I	SPI bus serial data input					
3	LDAC	ı	Load DAC latch control input (active low). When LDAC is low, the DAC latch is transparent, and the contents of the input register are transferred to the DAC latch. The DAC output changes to the corresponding level simultaneously when the DAC latch is updated.					
4	AGND	ı	Analog ground					
5	AV _{DD}	ı	Analog power supply					
6	V _{REFL} -S	I	Reference low input sense					
7	V _{REFH} -S	ı	Reference high input sense					
8	V _{OUT}	0	Output of output buffer					
9	R _{FB}	I	Feedback resistor connected to the inverting input of the output buffer.					
10	V _{REFL} -F	I	Reference low input force					
11	V _{REFH} -F	I.	Reference high input force					
12	NC	_	Do not connect.					
13	NC	_	Do not connect.					
14	RSTSEL	ı	Selects the value of the output from the V _{OUT} pin after power-on or hardware reset. If RSTSEL = IOV _{DD} , then register data = 20000h. If RSTSEL = DGND, then register data = 00000h.					
15	GAIN	I	Buffer gain setting. Gain = 1 when the pin is connected to DGND; Gain = 2 when the pin is connected to IOV _{DD} .					
16	USB/BTC	I	Input data format selection. Input data are straight binary format when the pin is connected to IOV _{DD} , and in twos complement format when the pin is connected to DGND.					
17	RST	ı	Reset input (active low). Logic low on this pin causes the device to perform a reset.					
18	PDN	I	Power-down input (active high). Logic high on this pin forces the device into power-down status. In power-down, the V_{OUT} pin connects to AGND through a $10k\Omega$ resistor.					
19	CS	I	SPI bus chip select input (active low). Data bits are not clocked into the serial shift register unless \overline{CS} is low. When \overline{CS} is high, SDO is in a high-impedance state.					
20	SDOSEL	ı	SPI serial data output selection. When SDOSEL is tied to IOV _{DD} , the contents of the existing input register are shifted out from the SDO pin; this is Stand-Alone mode. When SDOSEL is tied to DGND, the contents in the SPI input shift register are shifted out from the SDO pin; this is Daisy-Chain mode for daisy-chained communication.					
21	DV_DD	I	Digital power supply (connect to AV _{DD} , pin 5)					
22	DGND	ı	Digital ground					
23	SDO	0	SPI bus serial data output. Refer to the <i>Timing Diagrams</i> for further detail.					
24	IOV _{DD}	I	Interface power. Connect to +1.8V for 1.8V logic, +3V for 3V logic, and to +5V for 5V logic.					



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TIMING DIAGRAMS

Case 1: Standalone operation without SDO, LDAC tied low.



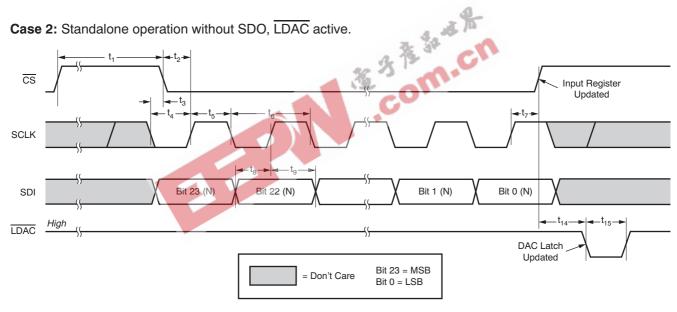


Figure 1. Timing Diagram for Standalone Operation without SDO



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TIMING CHARACTERISTICS for Figure 1 (1)(2)(3)

At -40°C to +85°C, unless otherwise noted.

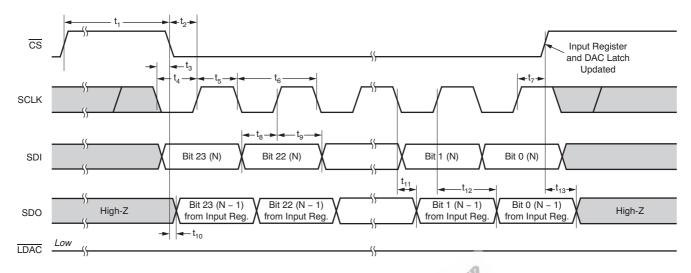
	PARAMETER	CONDITIONS	MIN	MAX	UNIT
4	Maximum clock frequency	$2.7 \le DV_{DD} < 3.6V$, $2.7 \le IOV_{DD} \le DV_{DD}$		40	MHz
f _{SCLK}	Maximum clock frequency	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$		50	MHz
t ₁	Minutes CO binb time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	50		ns
	Minumum CS high time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	30		ns
	CC falling adap to CCL V vising adap	$2.7 \le DV_{DD} < 3.6V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₂	CS falling edge to SCLK rising edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	8		ns
	SCLK falling edge to CS falling edge setup	$2.7 \le DV_{DD} < 3.6V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₃	time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₄	CCL // low time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
	SCLK low time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₅	SCLK high time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	15		ns
		$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
	CCL K avala tima	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	25		ns
t ₆	SCLK cycle time	$3.6 \le DV_{DD} \le 5.5V, 2.7 \le IOV_{DD} \le DV_{DD}$	20		ns
	SCLV vising adap to CS vising adap	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₇	SCLK rising edge to CS rising edge	$3.6 \le DV_{DD} \le 5.5V, 2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
	land data action time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	8		ns
t ₈	Input data setup time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
t ₉	lumit data hald time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
	Input data hold time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
	CS riging edge to LDAC folling edge	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₁₄	CS rising edge to LDAC falling edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
	LDAC pulse width	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	15		ns
t ₁₅	LDAC pulse width	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns

All input signals are specified with $t_R = t_F = 2$ ns (10% to 90% of IOV_{DD}) and timed from a voltage level of IOV_{DD}/2. Ensured by design. Not production tested. Sample tested during the initial release and after any redesign or process changes that may affect these parameters.



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Case 1: Standalone operation with output from SDO, LDAC tied low.



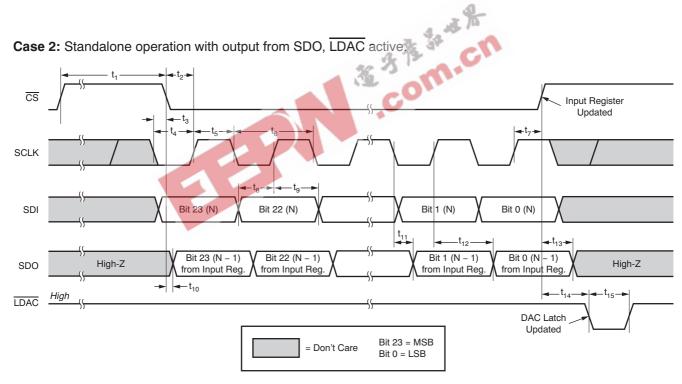


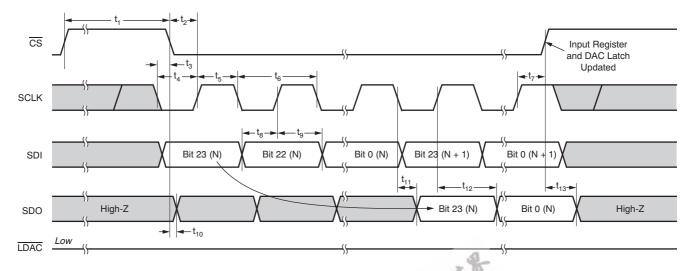
Figure 2. Timing Diagram for Standalone Operation with SDO

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Case 1: Daisy Chain, LDAC tied low.





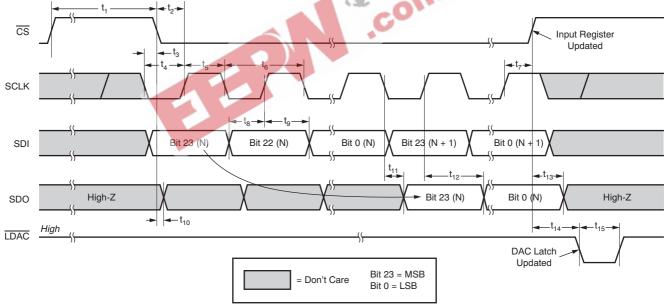


Figure 3. Timing Diagram for Daisy Chain Mode, Two Cascaded Devices



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TIMING CHARACTERISTICS for Figure 2 and Figure 3⁽¹⁾⁽²⁾⁽³⁾

At -40° C to $+85^{\circ}$ C, unless otherwise noted.

	PARAMETER	CONDITIONS	MIN	MAX	UNIT
	Maximum alask fraguency	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$		20	MHz
f _{SCLK}	Maximum clock frequency	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$		25	MHz
t ₁	Minusayura GC binb time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	50		ns
	Minumum CS high time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	30		ns
	OC falling advanta COLK rining advan	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₂	CS falling edge to SCLK rising edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	8		ns
	SCLK falling edge to CS falling edge setup	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₃	time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
	CCI I/ Iau tima	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	25		ns
t ₄	SCLK low time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	20		ns
	CCI I/ binb time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	25		ns
t ₅	SCLK high time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	20		ns
t ₆	SCLK cycle time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	50		ns
		$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	40		ns
	CCLIV vising adapta CC vising adap	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₇	SCLK rising edge to CS rising edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
	Land data action Con-	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
t ₈	Input data setup time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
	lanut data hald time	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
t ₉	Input data hold time	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
	SDO active from CS falling adag	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$		15	ns
t ₁₀	SDO active from CS falling edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$		10	ns
	CDO data valid from COLV follion odge	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$		20	ns
t ₁₁	SDO data valid from SCLK falling edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$		15	ns
	CDO data hald from COLV data and data	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	25		ns
t ₁₂	SDO data hold from SCLK rising edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	20		ns
t ₁₃	200111111111111111111111111111111111111	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$		8	ns
	SDO High-Z from CS rising edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$		5	ns
	CC vising adds to LDAC falling adds	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	10		ns
t ₁₄	CS rising edge to LDAC falling edge	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	5		ns
	LDAC pulpo width	$2.7 \le DV_{DD} < 3.6V, 2.7 \le IOV_{DD} \le DV_{DD}$	15		ns
t ₁₅	LDAC pulse width	$3.6 \le DV_{DD} \le 5.5V$, $2.7 \le IOV_{DD} \le DV_{DD}$	10		ns

⁽¹⁾ All input signals are specified with $t_R = t_F = 2ns$ (10% to 90% of IOV_{DD}) and timed from a voltage level of $IOV_{DD}/2$.

10

Product Folder Link(s): DAC9881

 ⁽²⁾ Ensured by design. Not production tested.
(3) Sample tested during the initial release and after any redesign or process changes that may affect these parameters.



PACKAGE OPTION ADDENDUM

21-May-2008

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp (3)
DAC9881IRGER	PREVIEW	VQFN	RGE	24	3000	TBD	Call TI	Call TI
DAC9881IRGET	PREVIEW	VQFN	RGE	24	250	TBD	Call TI	Call TI

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

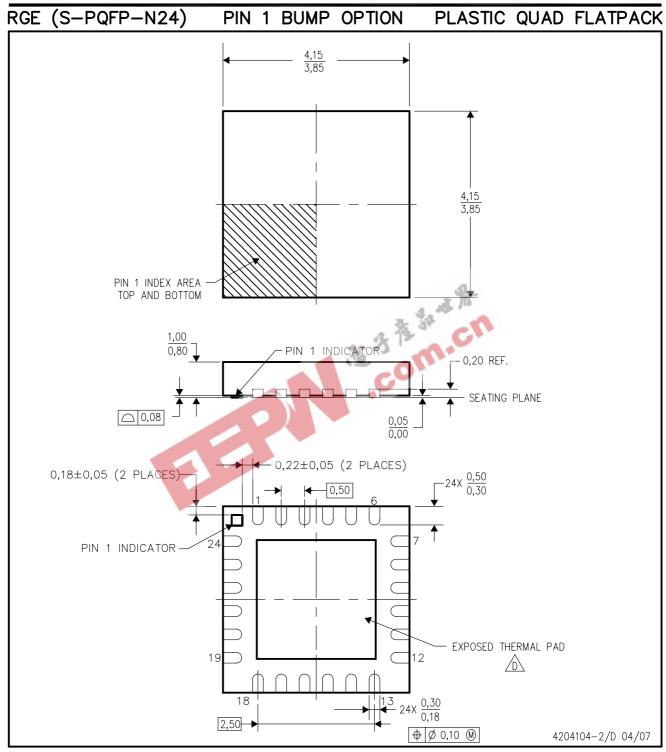
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based filp-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Quad Flatpack, No-Leads (QFN) package configuration.
- The package thermal pad must be soldered to the board for thermal and mechanical performance. See the Product Data Sheet for details regarding the exposed thermal pad dimensions.
- E. Falls within JEDEC MO-220.



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